



November 2007

# FDP2614

## 200V N-Channel PowerTrench MOSFET

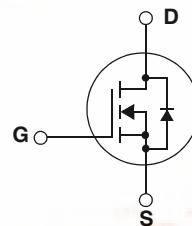
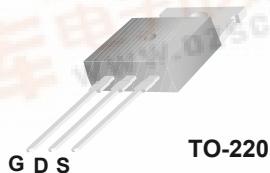
### General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.



### Application

- PDP application



### Description

- 62A, 200V,  $R_{DS(on)} = 22.9\text{m}\Omega$  @  $V_{GS} = 10\text{ V}$
- Fast switching speed
- Low gate charge
- High performance trench technology for extremely low  $R_{DS(on)}$
- High power and current handling capability
- RoHS compliant

### Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
$V_{DS}$	Drain-Source Voltage	200	V
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ ) - Continuous ( $T_C = 100^\circ\text{C}$ )	62 39.3	A A
$I_{DM}$	Drain Current - Pulsed	(Note 1)	see Figure 9
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	145
$dv/dt$	Peak Diode Recovery $dv/dt$	(Note 3)	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above $25^\circ\text{C}$	260 2.1	W W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

### Thermal Characteristics

Symbol	Parameter	Min.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	0.48	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	$^\circ\text{C}/\text{W}$

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP2614	FDP2614	TO-220	-	-	50

## Electrical Characteristics

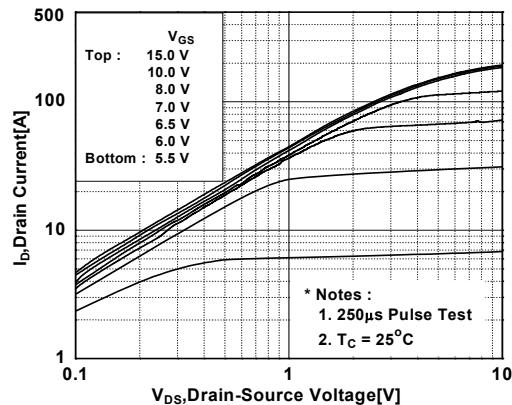
$T_C = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0\text{V}$ , $I_D = 250\mu\text{A}$ , $T_J = 25^\circ\text{C}$	200	--	--	V
$\frac{\Delta \text{BV}_{\text{DSS}}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.2	--	$\text{V}/^\circ\text{C}$
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 200\text{V}$ , $V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = 200\text{V}$ , $V_{\text{GS}} = 0\text{V}$ , $T_J = 125^\circ\text{C}$	--	--	10 500	$\mu\text{A}$ $\mu\text{A}$
$I_{\text{GSSF}}$	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30\text{V}$ , $V_{\text{DS}} = 0\text{V}$	--	--	100	nA
$I_{\text{GSSR}}$	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30\text{V}$ , $V_{\text{DS}} = 0\text{V}$	--	--	-100	nA
<b>On Characteristics</b>						
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 250\mu\text{A}$	3.0	4.0	5.0	V
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10\text{V}$ , $I_D = 31\text{A}$	--	22.9	27	$\text{m}\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{\text{DS}} = 10\text{V}$ , $I_D = 31\text{A}$	(Note 4)	--	72	--
<b>Dynamic Characteristics</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{\text{DS}} = 25\text{V}$ , $V_{\text{GS}} = 0\text{V}$ $f = 1.0\text{MHz}$	--	5435	7230	pF
$C_{\text{oss}}$	Output Capacitance		--	505	675	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		--	110	165	pF
<b>Switching Characteristics</b>						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 100\text{V}$ , $I_D = 62\text{A}$ $V_{\text{GS}} = 10\text{V}$ , $R_{\text{GEN}} = 25\Omega$	--	77	165	ns
$t_r$	Turn-On Rise Time		--	284	560	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	103	220	ns
$t_f$	Turn-Off Fall Time		--	162	335	ns
$Q_g$	Total Gate Charge	$V_{\text{DS}} = 100\text{V}$ , $I_D = 62\text{A}$ $V_{\text{GS}} = 10\text{V}$	--	76	99	nC
$Q_{\text{gs}}$	Gate-Source Charge		--	35	--	nC
$Q_{\text{gd}}$	Gate-Drain Charge		--	18	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current	$V_{\text{GS}} = 0\text{V}$ , $I_S = 62\text{A}$ $V_{\text{DS}} = 50\text{V}$ , $R_{\text{G}} = 25\Omega$ $dI_F/dt = 100\text{A}/\mu\text{s}$	--	--	62	A
$I_{\text{SM}}$	Maximum Pulsed Drain-Source Diode Forward Current		--	--	186	A
$V_{\text{SD}}$	Drain-Source Diode Forward Voltage		--	--	1.2	V
$t_{\text{rr}}$	Reverse Recovery Time		--	145	--	ns
$Q_{\text{rr}}$	Reverse Recovery Charge		(Note 4)	--	0.81	$\mu\text{C}$

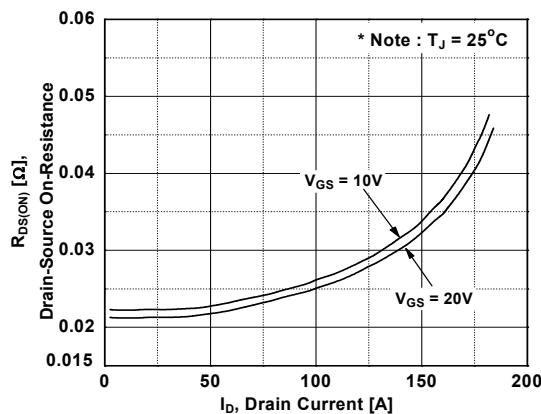
### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $L = 1\text{mH}$ ,  $I_A = 17\text{A}$ ,  $V_{\text{DD}} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{\text{SD}} \leq 62\text{A}$ ,  $di/dt \leq 100\text{A}/\mu\text{s}$ ,  $V_{\text{DD}} \leq \text{BV}_{\text{DSS}}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

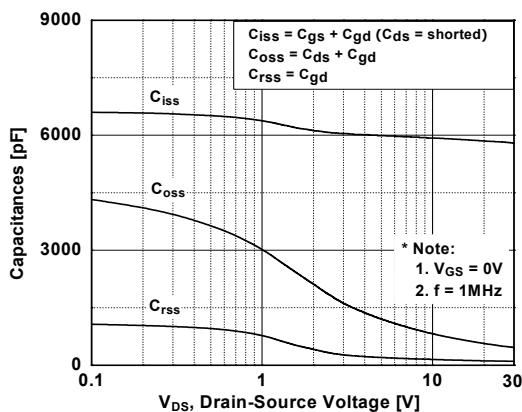
**Figure 1. On-Region Characteristics**



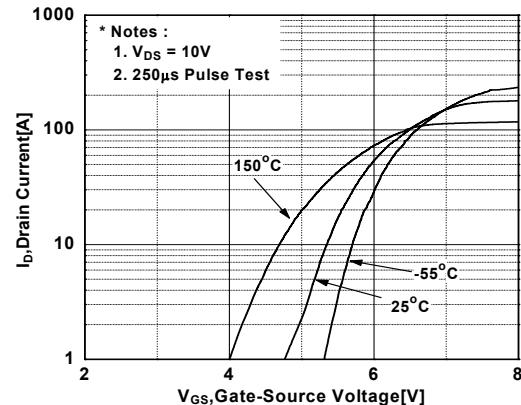
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



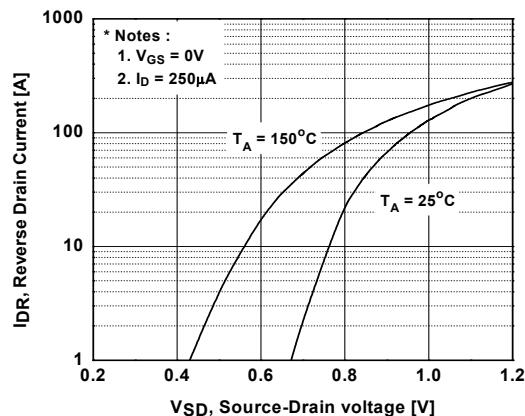
**Figure 5. Capacitance Characteristics**



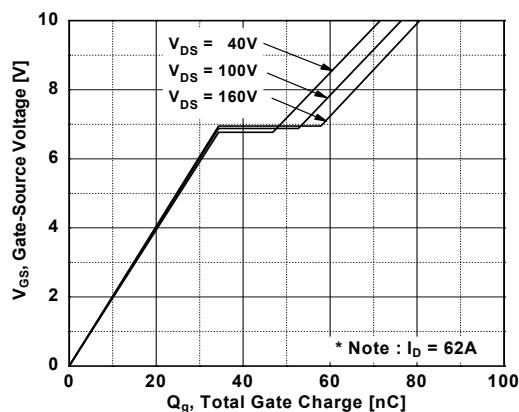
**Figure 2. Transfer Characteristics**



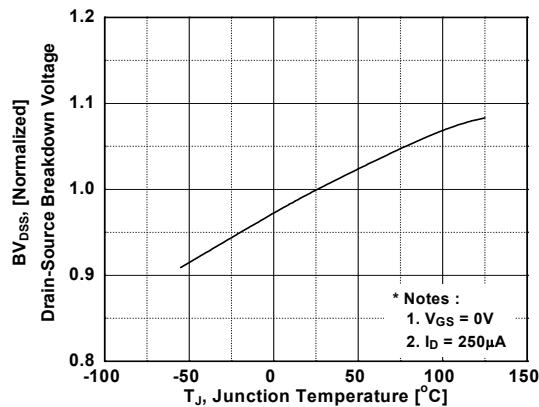
**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**



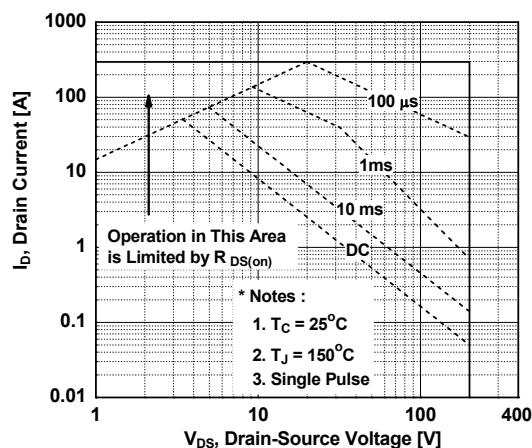
**Figure 6. Gate Charge Characteristics**



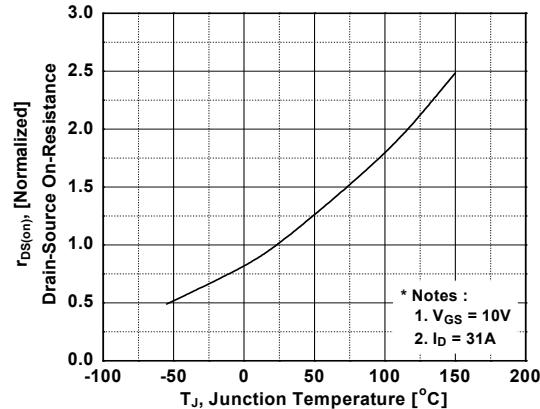
**Figure 7. Breakdown Voltage Variation vs. Temperature**



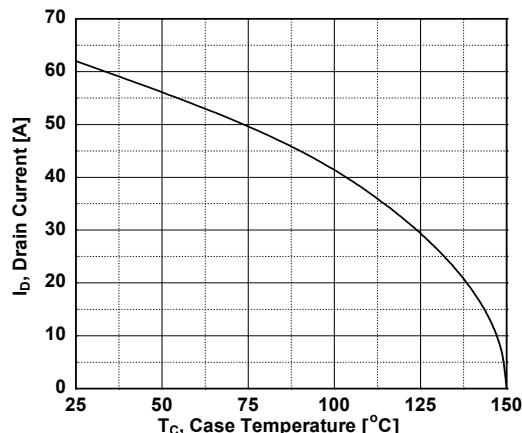
**Figure 9. Maximum Safe Operating Area**



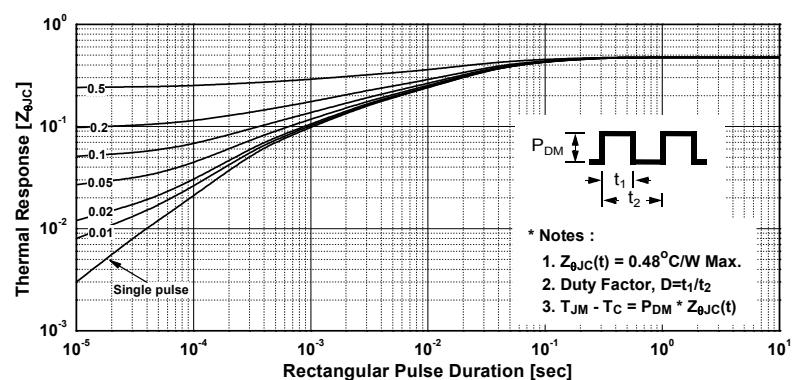
**Figure 8. On-Resistance Variation vs. Temperature**



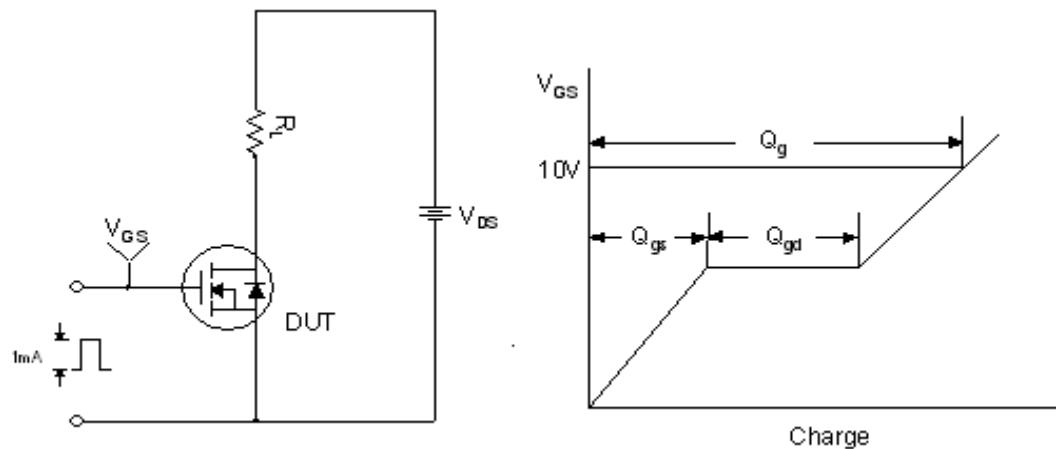
**Figure 10. Maximum Drain Current vs. Case Temperature**



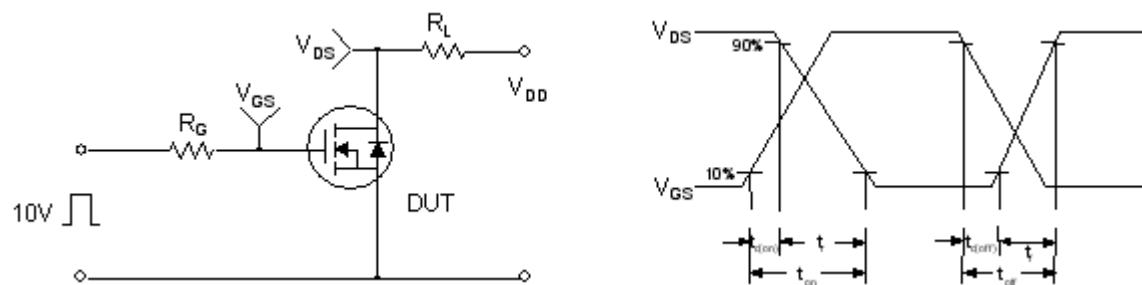
**Figure 11. Transient Thermal Response Curve**



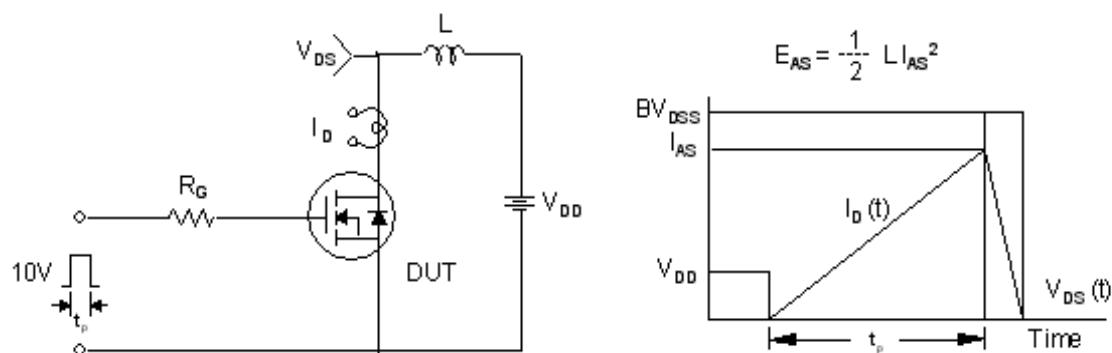
**Gate Charge Test Circuit & Waveform**



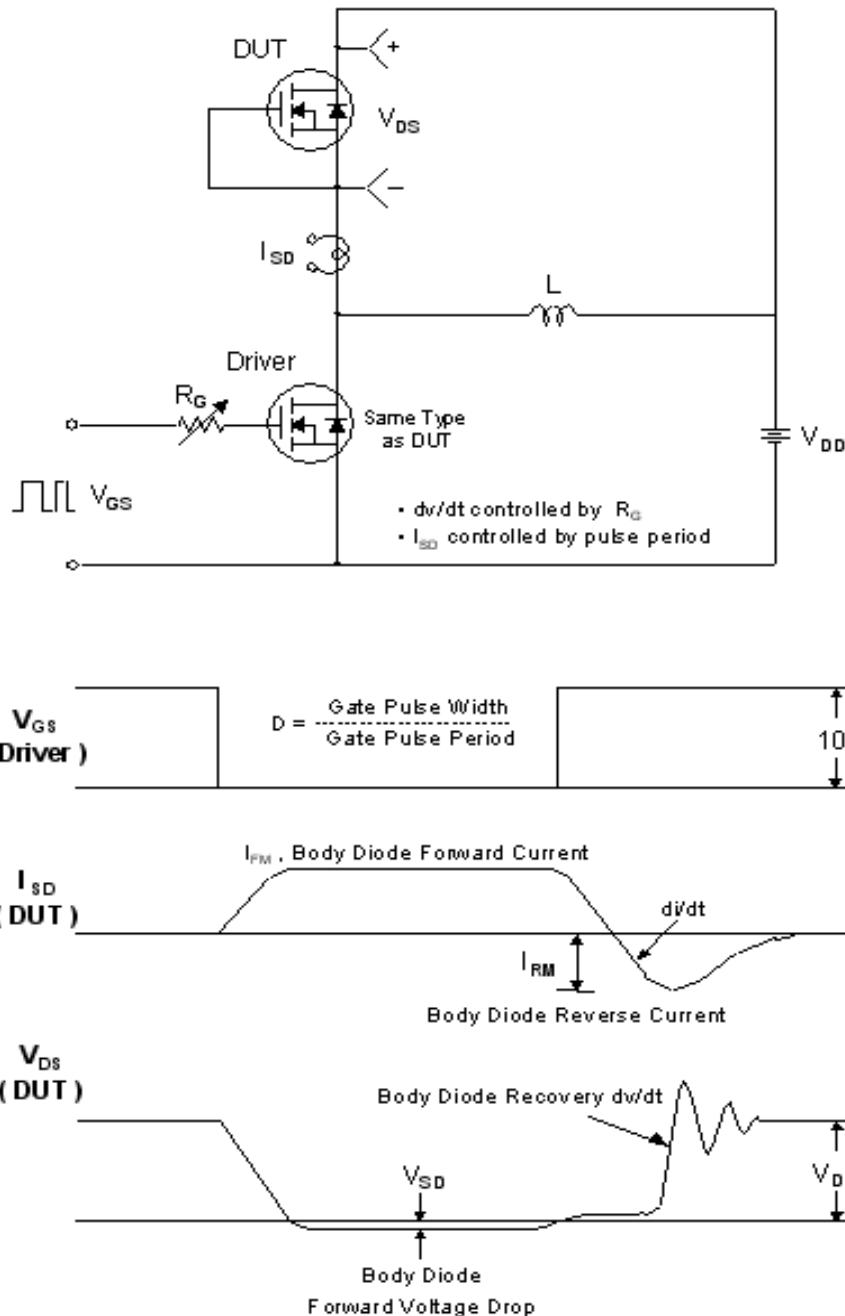
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**

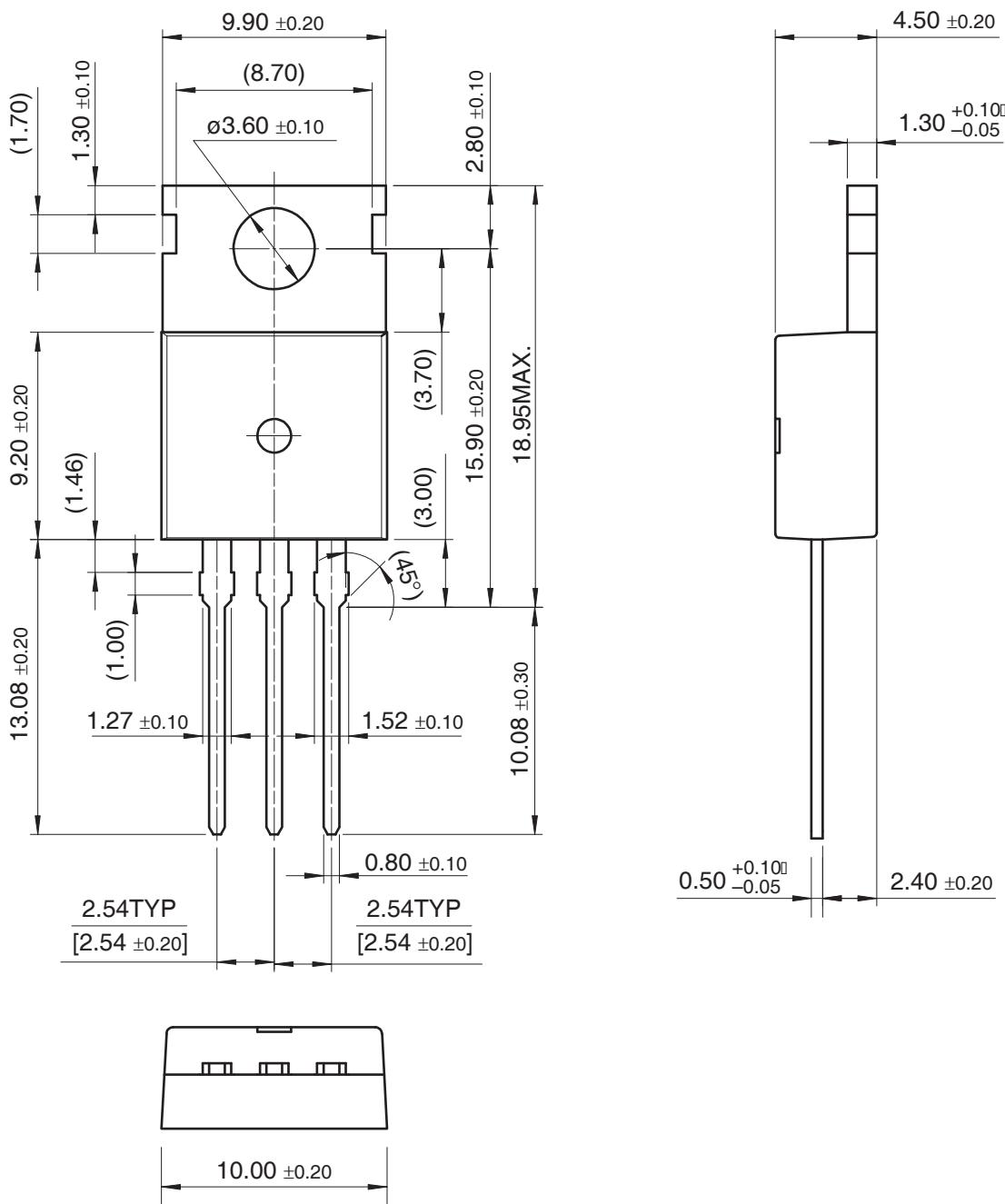


Peak Diode Recovery dv/dt Test Circuit & Waveforms



### Mechanical Dimensions

**TO-220**





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